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A Simple Solution to the Fresnel-Kirchoff Diffraction Integral for Application to Refraction-Enhanced Radiography

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We present a simple solution to the one-dimensional Fresnel-Kirchoff diffraction integral with minimal approximations that are appropriate for the geometrical optics regime, where phase contrast enhancements can be considered to be caused by refraction by a semi-transparent object. We demonstrate its accuracy by comparison to brute-force numerical raytrace and diffraction calculations of a representative simulated object, and show excellent agreement for spatial scales corresponding to Fresnel numbers greater than unity. The result represents a significant improvement over approximate formulas typically used in analysis of refraction-enhanced radiographs, particularly for radiography of transient phenomena in objects that strongly refract and show significant absorption.

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Backlit projection x-ray radiography of absorbing objects has a long history dating back to Röntgen. In the limit of high x-ray energy, transmission of backlight x-rays along a line of sight is $e^{-\tau}$, where τ is the line-integrated opacity of the object that depends on the object material properties and the backlight x-ray energy. Treating τ as one-dimensional is a natural simplification for imaging spherically-symmetric objects, in which case $\tau(x)$ is the Abel transform of a radial attenuation coefficient. This class of objects is important for radiography of inertial-confinement fusion (ICF) plasmas [1-3].

This approach fails when wave effects becomes significant. From a diffraction perspective, a light wave from a backlight source experiences a local phase shift $\phi(x)$ relative to vacuum in passing through a semi-transparent object, and over sufficient propagation distances the phase perturbations generate light intensity perturbations in a detector plane. From a geometrical optics perspective, straight rays from the backlight source are refracted by transverse density gradients in the object, and this adds or subtracts light intensity locally in a detector plane. The two perspectives are equivalent for object spatial scales L , propagation distances q , and light wavelengths λ that correspond to Fresnel numbers $F = L^2/q\lambda \gg 1$. This refraction-enhanced imaging regime is of interest in fields such as biological and medical imaging and astronomy [4-9], and is of greatest interest for ICF research [10].

The transport of intensity equation (TIE) [11-13] is typically used to interpret the transmitted intensity pattern $I(x,z)$ along the z -axis line of sight,

$$\frac{\partial I}{\partial z} = \frac{-\lambda}{2\pi} \left(I \frac{d^2 \phi}{dx^2} + \frac{\partial I}{\partial x} \frac{d\phi}{dx} \right) \quad (1)$$

Direct application of eq. (1) is limited to small offsets and/or multiple detector planes. When absorption is negligible and phase shifts are small, the intensity $I(x,q) = 1 - (\lambda q/2\pi) d^2 \phi(x,0)/dx^2$ [4,14,15], and modifications to

allow for absorption can also be included [16-18]. Retrieval of $\phi(x)$ can then proceed using a variety of approaches. An alternative approach is to map deflections by scanning across the object [5,14], and this provides a direct measure of $d\phi/dx$ when the approach is practical.

Transient phenomena in strongly refracting and absorbing objects present a particular problem, because scanning or detector-plane shifting techniques cannot be used, and $\phi(x)$ and $\tau(x)$ must generally be found iteratively using model functions in a forward fit. Approximate formulas used for calculating $I(x)$ fail because the required approximations do not hold, and in this case numerical forward calculations of $I(x)$ using either eq. (1), numerical raytracing, or direct solution of the Fresnel-Kirchoff (FK) integral [19,20] must be used. This process is time-consuming, particularly when model functions are developed without assumed analytic forms in genetic algorithm search and reconstruction procedures [21]. We therefore pursue the derivation of a simple formula for the radiograph intensity distribution due to a strongly refracting and absorbing object in an arbitrary detector plane that is appropriate for the refraction-enhanced imaging regime.

We begin with the one-dimensional complex form of the FK diffraction integral for an infinitely-distant source backlighting an absorbing phase object in vacuum, with phase and opacity variations along the x -axis immediately in front of the object, and look for solutions to the free-space propagation problem that leads to an absorption radiograph with refractive enhancements. The field at location x in a detector plane a distance q behind the object can be written as,

$$E(x) = C \int_{-\infty}^{\infty} \left(\frac{1}{2} + \frac{1}{2\sqrt{1+(x-x_o)^2/q^2}} \right) e^{\frac{-\tau(x_o)}{2}} e^{i \left(\frac{2\pi q}{\lambda} \sqrt{1 + \frac{(x-x_o)^2}{q^2}} + \phi(x_o) \right) \frac{\pi}{2}} dx_o \quad (2)$$

where C is a normalization constant and x_o is the coordinate in the object plane. We assume $(x - x_o)^2 \ll q^2$

and $\lambda \ll q$, eliminating the slowly-varying bracketed obliquity factor and simplifying the phase exponential. When $\phi(x_0) = \text{constant}$ and $\tau(x_0) = 0$, we can solve the integral analytically [22] and determine C such that the intensity $I(x) = |E(x)E^*(x)|$ is unity. Neglecting phase factors that will cancel in $I(x)$ throughout, we have,

$$E(x) = \frac{1}{\sqrt{\lambda q}} \int_{-\infty}^{\infty} e^{-\frac{\tau(x_0)}{2}} e^{i\left(\phi(x_0) + \frac{\pi(x-x_0)^2}{\lambda q}\right)} dx_0 \quad (3)$$

We now work with eq. (3) directly in coordinate space, rather than with transforms in Fourier space. We change variables with $u = (x - x_0)/a$, yielding

$$E(x) = \frac{1}{\sqrt{\pi}} \int_{-\infty}^{\infty} e^{-\frac{\tau(x-au)}{2}} e^{i\left(\phi(x-au) + u^2\right)} du \quad (4)$$

with $a = \sqrt{\lambda q/\pi}$. We first expand ϕ about x , setting derivatives higher than $\phi_2 = d^2\phi/dx^2$ equal to zero,

$$E(x_d) = \frac{1}{\sqrt{\pi}} \int_{-\infty}^{\infty} e^{-\frac{\tau(x_d-au)}{2}} e^{i\left(\phi(x_d) - au\phi_1(x_d) + (1 + \frac{a^2\phi_2(x_d)}{2})u^2\right)} du \quad (5)$$

Eq. (5) can be rewritten as,

$$\begin{aligned} E(x) &= \frac{1}{\sqrt{\pi}} \int_{-\infty}^{\infty} e^{-\frac{\tau(x-au)}{2}} e^{i\left(\left(1 + \frac{a^2\phi_2(x)}{2}\right)u^2 - au\phi_1(x)\right)} du \\ &= \frac{1}{\sqrt{\lambda q}} \int_{-\infty}^{\infty} e^{-\frac{\tau(x_0)}{2}} e^{i\left(\frac{\sqrt{1 + \frac{a^2\phi_2(x)}{2}}(x-x_0)}{a} - \frac{a\phi_1(x)}{2\sqrt{1 + \frac{a^2\phi_2(x)}{2}}}\right)^2} dx_0 \end{aligned} \quad (6)$$

We recognize that eq. (6) implies that object points near $x_0 = x$ contribute most to the field (u near zero) at a detector location x' that is different from x , and that the intensity pattern will therefore be shifted locally by an amount that eliminates the second term in the exponential. We find the shift by writing $E(x')$, with $x' = x + a^2\phi_1(x)/2$. Again neglecting third- and higher-order derivatives of $\phi(x)$, this is,

$$\begin{aligned} E(x') &= E\left(x + \frac{a^2\phi_1(x)}{2}\right) = \frac{1}{\sqrt{\lambda q}} \int_{-\infty}^{\infty} e^{-\frac{\tau(x_0)}{2}} e^{i\left(1 + \frac{a^2\phi_2(x)}{2}\right)\left(\frac{(x-x_0)}{a}\right)^2} dx_0 \\ &= \frac{1}{\sqrt{1 + \frac{a^2}{2}\phi_2(x)}} \frac{1}{\sqrt{\pi}} \int_{-\infty}^{\infty} e^{-\frac{\tau(x-bu)}{2}} e^{iu^2} du \end{aligned} \quad (7)$$

where $b^2 = a^2/(1 + a^2\phi_2(x)/2)$. We next expand $\tau(x)$ about x and set derivatives higher than $\tau_2 = d^2\tau/dx^2$ equal to zero, giving,

$$E(x') = \frac{be^{-\frac{\tau(x)}{2}}}{\sqrt{\lambda q}} \int_{-\infty}^{\infty} e^{-\left(\frac{b^2\tau_2}{4}u^2 - \frac{b\tau_1}{2}u\right)} e^{-iu^2} du \quad (8)$$

The integral can be solved analytically [22], and the resulting intensity is,

$$\begin{aligned} I(x') &= I\left(x + \frac{\lambda q\phi_1}{2\pi}\right) = \frac{e^{-\tau}}{\left|1 + \frac{\lambda q\phi_2}{2\pi}\right|} K(x) \\ K(x) &= \frac{e^{\frac{\lambda^2 q^2}{32\pi^2} \left(\frac{\tau_1^2 \tau_2}{\left(1 + \frac{\lambda q\phi_2}{2\pi}\right)^2} + \frac{\lambda^2 q^2 \tau_2^2}{16\pi^2}\right)}}{\sqrt{1 + \frac{\lambda^2 q^2 \tau_2^2}{16\pi^2 \left(1 + \frac{\lambda q\phi_2}{2\pi}\right)^2}}} \approx 1 + \frac{1}{8} \left(\frac{\lambda q}{2\pi}\right)^2 \frac{\tau_2(\tau_1^2 - \tau_2)}{\left(1 + \frac{\lambda q\phi_2}{2\pi}\right)^2} \end{aligned} \quad (9)$$

where τ and all derivatives are evaluated at x . Eq. (9) is an exact solution for the intensity pattern derived from fields given by the FK integral of eq. (3), assuming only that terms involving third- and higher-order derivatives in the expansions of $\phi(x+\delta)$ and $\tau(x+\delta)$ about x are all zero. From eq. (4), it is therefore well-suited to the geometrical optics regime of Fresnel numbers much larger than unity.

The term $K(x)$ is second-order in λq and involves squares of first and second derivatives of the opacity profile, and in most cases of practical interest can be neglected. Eq. (9) then reduces to a particularly simple form,

$$I\left(x + \frac{\lambda q}{2\pi} \frac{d\phi(x)}{dx}\right) = \frac{e^{-\tau(x)}}{\left|1 + \frac{\lambda q}{2\pi} \frac{d^2\phi(x)}{dx^2}\right|} \quad (10)$$

Eq. (10) differs in three important respects from approximate equations used to describe intensity patterns in refraction-enhanced imaging [13-20]; the intensity pattern is shifted on the left-hand side by an amount proportional to $d\phi/dx$, the right-hand side involves $1/|1 + (\lambda q/2\pi)d^2\phi/dx^2|$ rather than $1 - (\lambda q/2\pi)d^2\phi/dx^2$, and absorption is included by simply multiplying the right-hand side by an exponential absorption factor. Where the second derivative term in the denominator of the right-hand side is less than negative one, a cusp is formed and the intensity profile forms caustics. In these regions the intensities of the folds simply add, though here the neglect of third- and higher-order derivatives of $\phi(x)$ and $\tau(x)$ in this treatment may become questionable.

Approximate solutions for $I(x)$, rather than $I(x')$, can be attempted, and the first approximation for infinitesimal q recovers the TIE eq. (1), but eq. (10) is perhaps most useful as-written for forward-fit iterative solutions to the inversion problem of determining $\phi(x)$ and $\tau(x)$ from intensity radiograph data. Given trial functions $\phi(x)$ and $\tau(x)$, the intensity pattern can be easily calculated with minimal restrictions on their higher-order derivatives, allowing rapid iteration to optimal $\phi(x)$ and $\tau(x)$ functions by generating regridded radiographs $I(x')$ that best match experimental data. The equation is equally appropriate for point-source projection radiography when x is the detector location scaled back to the object through the magnification and when q is replaced by $f = pq/(p+q)$, where p is the source/object distance [10,15,16].

We can demonstrate the accuracy of eq. (10) using simulations appropriate to radiography of an ICF implosion [10]. Fig. 1(a) shows typical expected radial electron density and absorption coefficient (at $E = 10$ keV) profiles along with their corresponding line-integrated $\phi(x)$ and $\tau(x)$ profiles that are the Abel transforms of the radial profiles. We see that this object is strongly refracting and absorbing when viewed along the limb, with ~ 300 radians of phase shift, peak optical depths > 1 , and spatial scales down to $\sim 1 \mu\text{m}$. Fig. 1(b) shows a comparison of expected radiograph profiles from a 10 keV collimated x-ray source backlighting the implosion onto a detector $q = 10$ mm from the object (equivalent to point-source backlighting at high magnification, with $p = 10$ mm), calculated in various ways; numerical raytracing [10,23], direct application of the FK integral eq. (2), eq. (10), and

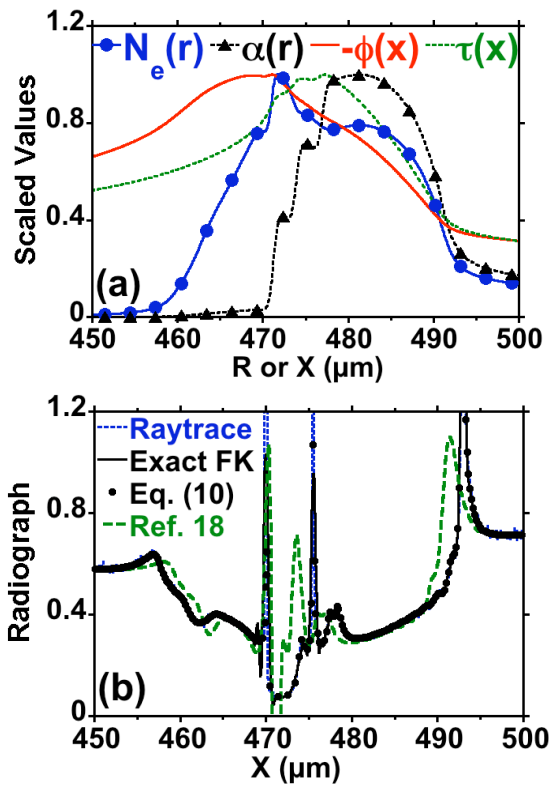


Fig 1: (a) Radial electron density $N_e(r)/2.6 \times 10^{24} \text{ cm}^{-3}$, radial absorption coefficient $\alpha(r)/3.9 \times 10^{-3} \mu\text{m}^{-1}$, phase shift $-\phi(x)/285$ radians, and opacity $\tau(x)/1.12$, and (b) simulated radiographs described in the text.

eq. (33) of [18] that derives from [17] for infinite source distance. We see that eq. (10) duplicates a numerical raytrace even in the sharply-varying caustic region near $x = 470 \mu\text{m}$, and duplicates direct application of the FK integral except where $\phi(x)$ significantly varies over μm spatial scales corresponding to Fresnel numbers < 1 , where the higher-order derivatives neglected in the derivation of eq. (10) are significant. It also significantly improves upon previous approximate formulas, which misplace the peaks and dips and calculate negative intensities near $x = 470 \mu\text{m}$.

In summary, we have derived and demonstrated a simple analytical formula to predict the radiograph profile of an arbitrary absorbing and phase-shifting object, that is an exact solution to the Fresnel-Kirchoff integral with well-specified approximations appropriate to the refraction-enhanced imaging regime. This represents a significant improvement over earlier approximate formulas for radiography of transient phenomena in objects that are strongly refracting and absorbing, and is well-suited to iterative search and reconstruction procedures that optimize the phase and opacity profiles to best-fit individual measured radiographs. This work was performed under the auspices of the U.S. Department of Energy by Lawrence Livermore National Laboratory under contract DE-AC52-07NA27344.

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